


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/705,899	LEE ET AL.	
	Examiner	Art Unit	
	HOAN C. NGUYEN	2871	

SEARCHED			
Class	Subclass	Date	Examiner
349	139	11/28/2005	CHN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East search in US-PGPUB, USPAT, EPO, JPO, Derwent and IBM_TDB	11/28/2005	CHN